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RoHS

3-Axis, 12-bit/8-bit Digital Accelerometer

 The MMA8452Q is a smart low-power, three-axis, capacitive micromachined accelerometer with 12 bits of resolution. This accelerometer is packed with embedded functions with flexible user programmable options, configurable to two interrupt pins. Embedded interrupt functions allow for overall power savings relieving the host processor from continuously polling data.

The MMA8452Q has user selectable full scales of ±2g/±4g/±8g with high pass filtered data as well as non filtered data available real-time. The device can be configured to generate inertial wakeup interrupt signals from any combination of the configurable embedded functions allowing the MMA8452Q to monitor events and remain in a low power mode during periods of inactivity. The MMA8452Q is available in a 3 mm x 3 mm x 1 mm QFN package.

Features

- 1.95 V to 3.6 V supply voltage
- 1.6 V to 3.6 V interface voltage
- $\pm 2g/\pm 4g/\pm 8g$ dynamically selectable full-scale
- Output Data Rates (ODR) from 1.56 Hz to 800 Hz
- 99μg/√Hz noise
- 12-bit and 8-bit digital output
- $\overline{f}C$ digital output interface (operates to 2.25 MHz with 4.7 k Ω pullup)
- Two programmable interrupt pins for six interrupt sources
- Three embedded channels of motion detection
	- Freefall or Motion Detection: 1 channel
	- Pulse Detection: 1 channel
	- Jolt Detection: 1 channel
- Orientation (Portrait/Landscape) detection with set hysteresis
- Automatic ODR change for Auto-WAKE and return to SLEEP
- High Pass Filter Data available real-time
- Self-Test
- RoHS compliant
- Current Consumption: 6μA 165 μA

Typical Applications

- eCompass applications
- Static orientation detection (Portrait/Landscape, Up/Down, Left/Right, Back/ Front position identification)
- Notebook, eReader and Laptop Tumble and Freefall Detection
- Real-time orientation detection (virtual reality and gaming 3D user position feedback)
- Real-time activity analysis (pedometer step counting, freefall drop detection for HDD, dead-reckoning GPS backup)
- Motion detection for portable product power saving (Auto-SLEEP and Auto-WAKE for cell phone, PDA, GPS, gaming)
- Shock and vibration monitoring (mechatronic compensation, shipping and warranty usage logging)
- User interface (menu scrolling by orientation change, tap detection for button replacement)

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Contents

Application Notes for Reference

The following is a list of Freescale Application Notes written for the MMA8451, 2, 3Q:

- **AN4068**, Embedded Orientation Detection Using the MMA8451, 2, 3Q
- **AN4069**, Offset Calibration of the MMA8451, 2, 3Q
- **AN4070**, Motion and Freefall Detection Using the MMA8451, 2, 3Q
- **AN4071**, High Pass Data and Functions Using the MMA8451, 2,3Q
- **AN4072**, MMA8451, 2, 3Q Single/Double and Directional Tap Detection
- **AN4073**, Using the 32 Sample First In First Out (FIFO) in the MMA8451Q
- **AN4074**, Auto-Wake/Sleep Using the MMA8451, 2, 3Q
- **AN4075**, How Many Bits are Enough? The Trade-off Between High Resolution and Low Power Using Oversampling Modes
- **AN4076**, Data Manipulation and Basic Settings of the MMA8451, 2, 3Q
- **AN4077**, MMA8451, 2, 3Q Design Checklist and Board Mounting Guidelines

1 Block Diagram and Pin Description

DIRECTION OF THE DETECTABLE ACCELERATIONS

(TOP VIEW)

(BOTTOM VIEW)

[Figure 3](#page-3-0) shows the device configuration in the 6 different orientation modes. These orientations are defined as the following: PU = Portrait Up, LR = Landscape Right, PD = Portrait Down, LL = Landscape Left, BACK and FRONT side views. There are several registers to configure the orientation detection and are described in detail in the register setting section.

Figure 4. Application Diagram

Table 1. Pin Description

The device power is supplied through VDD line. Power supply decoupling capacitors (100 nF ceramic plus 4.7 µF bulk, or a single 4.7 µF ceramic) should be placed as near as possible to the pins 1 and 14 of the device.

The control signals SCL, SDA, and SA0 are not tolerant of voltages more than VDDIO + 0.3 V. If VDDIO is removed, the control signals SCL, SDA, and SA0 will clamp any logic signals with their internal ESD protection diodes.

The functions, the threshold and the timing of the two interrupt pins (INT1 and INT2) are user programmable through the $I²C$ interface. The SDA and SCL I²C connections are open drain and therefore require a pullup resistor as shown in the application diagram in [Figure 4](#page-3-1).

1.1 Soldering Information

The QFN package is compliant with the RoHS standard. Please refer to AN4077.

2 Mechanical and Electrical Specifications

2.1 Mechanical Characteristics

Table 2. Mechanical Characteristics @ VDD = 2.5 V, VDDIO = 1.8 V, T = 25°C unless otherwise noted .

1. Dynamic Range is limited to 4g when the Low Noise bit in Register 0x2A, bit 2 is set.

2. Sensitivity remains in spec as stated, but changing Oversampling mode to Low Power causes 3% sensitivity shift. This behavior is also seen when changing from 800 Hz to any other data rate in the Normal, Low Noise + Low Power or High Resolution mode.

3. Before board mount.

4. Post Board Mount Offset Specifications are based on an 8 Layer PCB, relative to 25°C.

5. Self-Test is one direction only.

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2.2 Electrical Characteristics

Table 3. Electrical Characteristics @ VDD = 2.5 V, VDDIO = 1.8 V, T = 25°C unless otherwise noted.

1. There is no requirement for power supply sequencing. The VDDIO input voltage can be higher than the VDD input voltage.

2.3 I2C Interface Characteristic

Table 4. I2C Slave Timing Values(1)

1. All values referred to VIH (min) and VIL (max) levels.

2. $t_{HD;DAT}$ is the data hold time that is measured from the falling edge of SCL, applies to data in transmission and the acknowledge.

3. The maximum t_{HD:DAT} could be 3.45 μs and 0.9 μs for Standard mode and Fast mode, but must be less than the maximum of t_{VD:DAT} or t_{VD:ACK} by a transition time.

4. $t_{VD;DAT}$ = time for Data signal from SCL LOW to SDA output (HIGH or LOW, depending on which one is worse).

5. $t_{VD:ACK}$ = time for Acknowledgement signal from SCL LOW to SDA output (HIGH or LOW, depending on which one is worse).

6. A Fast mode I²C device can be used in a Standard mode I²C system, but the requirement t_{SU;DAT} 250 ns must then be met. This will automatically be the case if the device does not stretch the LOW period of the SCL signal. If such a device does stretch the LOW period of the SCL signal, it must output the next data bit to the SDA line $t_r(max) + t_{SU;DAT} = 1000 + 250 = 1250$ ns (according to the Standard mode I²C specification) before the SCL line is released. Also the acknowledge timing must meet this setup time

7. Cb = total capacitance of one bus line in pF.

8. The maximum t_f for the SDA and SCL bus lines is specified at 300 ns. The maximum fall time for the SDA output stage t_f is specified at 250 ns. This allows series protection resistors to be connected in between the SDA and the SCL pins and the SDA/SCL bus lines without exceeding the maximum specified t_{f} .

Figure 5. I2C Slave Timing Diagram

2.4 Absolute Maximum Ratings

Stresses above those listed as "absolute maximum ratings" may cause permanent damage to the device. Exposure to maximum rating conditions for extended periods may affect device reliability.

Table 5. Maximum Ratings

Table 6. ESD and Latchup Protection Characteristics

A.

This device is sensitive to mechanical shock. Improper handling can cause permanent damage of the part or cause the part to otherwise fail.

This device is sensitive to ESD, improper handling can cause permanent damage to the part.

3 Terminology

3.1 Sensitivity

The sensitivity is represented in counts/g. In 2g mode the sensitivity is 1024 counts/g. In 4g mode the sensitivity is 512 counts/g and in 8g mode the sensitivity is 256 counts/g.

3.2 Zero-g Offset

Zero-g Offset (TyOff) describes the deviation of an actual output signal from the ideal output signal if the sensor is stationary. A sensor stationary on a horizontal surface will measure 0g in X-axis and 0g in Y-axis whereas the Z-axis will measure 1g. The output is ideally in the middle of the dynamic range of the sensor (content of OUT Registers 0x00, data expressed as 2's complement number). A deviation from ideal value in this case is called Zero-g offset. Offset is to some extent a result of stress on the MEMS sensor and therefore the offset can slightly change after mounting the sensor onto a printed circuit board or exposing it to extensive mechanical stress.

3.3 Self-Test

Self-Test checks the transducer functionality without external mechanical stimulus. When Self-Test is activated, an electrostatic actuation force is applied to the sensor, simulating a small acceleration. In this case the sensor outputs will exhibit a change in their DC levels which are related to the selected full scale through the device sensitivity. When Self-Test is activated, the device output level is given by the algebraic sum of the signals produced by the acceleration acting on the sensor and by the electrostatic test-force.

4 Modes of Operation

Figure 6. MMA8452Q Mode Transition Diagram

Table 7. Mode of Operation Description

Mode	I ² C Bus State	VDD	VDDIO	Function Description
OFF	Powered Down	<1.8 V	VDDIO Can be > VDD	The device is powered off. All analog and digital blocks are shutdown. I ² C bus inhibited.
STANDBY	$I2C$ communication with MMA8452Q is possible	ON	$VDDIO = High$ $VDD = High$ ACTIVE bit is cleared	Only digital blocks are enabled. Analog subsystem is disabled. Internal clocks disabled.
ACTIVE (WAKE/SLEEP)	$I2C$ communication with MMA8452Q is possible	ON	$VDDIO = High$ $VDD = High$ ACTIVE bit is set	All blocks are enabled (digital, analog).

All register contents are preserved when transitioning from ACTIVE to STANDBY mode. Some registers are reset when transitioning from STANDBY to ACTIVE. These are all noted in the device memory map register table. The SLEEP and WAKE modes are ACTIVE modes. For more information on how to use the SLEEP and WAKE modes and how to transition between these modes please refer to the functionality section of this document.

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5 Functionality

The MMA8452Q is a low-power, digital output 3-axis linear accelerometer with a I²C interface and embedded logic used to detect events and notify an external microprocessor over interrupt lines. The functionality includes the following:

- 8-bit or 12-bit data which includes High Pass Filtered data
- 4 different oversampling options for compromising between resolution and current consumption based on application requirements
- Additional Low Noise mode that functions independently of the Oversampling modes for higher resolution
- Low Power and Auto-WAKE/SIEEP for conservation of current consumption
- Single/Double tap with directional information 1 channel
- Motion detection with directional information or Freefall 1 channel
- Transient/Jolt detection based on a high pass filter and settable threshold for detecting the change in acceleration above a threshold with directional information 1 channel
- Portrait/Landscape detection with trip points fixed at 30° and 60° for smooth transitions between orientations.

All functionality is available in 2g, 4g or 8g dynamic ranges. There are many configuration settings for enabling all the different functions. Separate application notes have been provided to help configure the device for each embedded functionality.

5.1 Device Calibration

The device interface is factory calibrated for sensitivity and Zero-g offset for each axis. The trim values are stored in Non Volatile Memory (NVM). On power-up, the trim parameters are read from NVM and applied to the circuitry. In normal use, further calibration in the end application is not necessary. However, the MMA8452Q allows the user to adjust the Zero-g offset for each axis after power-up, changing the default offset values. The user offset adjustments are stored in 6 volatile registers. For more information on device calibration, refer to Freescale application note, AN4069.

5.2 8-bit or 12-bit Data

The measured acceleration data is stored in the OUT_X_MSB, OUT_X_LSB, OUT_Y_MSB, OUT_Y_LSB, OUT_Z_MSB, and OUT_Z_LSB registers as 2's complement 12-bit numbers. The most significant 8-bits of each axis are stored in OUT_X (Y, Z)_MSB, so applications needing only 8-bit results can use these 3 registers and ignore OUT_X,Y, Z_LSB. To do this, the F_READ bit in CTRL_REG1 must be set. When the F_READ bit is cleared, the fast read mode is disabled.

When the full-scale is set to 2g, the measurement range is -2g to +1.999g, and each count corresponds to 1g/1024 (1 mg) at 12-bits resolution. When the full-scale is set to 8g, the measurement range is -8g to +7.996g, and each count corresponds to 1g/256 (3.9 mg) at 12-bits resolution. The resolution is reduced by a factor of 16 if only the 8-bit results are used. For more information on the data manipulation between data formats and modes, refer to Freescale application note, AN4076. There is a device driver available that can be used with the Sensor Toolbox demo board (LFSTBEB8451, 2, 3Q) with this application note.

5.3 Low Power Modes vs. High Resolution Modes

The MMA8452Q can be optimized for lower power modes or for higher resolution of the output data. High resolution is achieved by setting the LNOISE bit in Register 0x2A. This improves the resolution but be aware that the dynamic range is limited to 4g when this bit is set. This will affect all internal functions and reduce noise. Another method for improving the resolution of the data is by oversampling. One of the oversampling schemes of the data can activated when MODS = 10 in Register 0x2B which will improve the resolution of the output data only. The highest resolution is achieved at 1.56 Hz.

There is a trade-off between low power and high resolution. Low Power can be achieved when the oversampling rate is reduced. When MODS = 11 the lowest power is achieved. The lowest power is achieved when the sample rate is set to 1.56 Hz. For more information on how to configure the MMA8452Q in Low Power mode or High Resolution mode and to realize the benefits, refer to Freescale application note, AN4075.

5.4 Auto-WAKE/SLEEP Mode

The MMA8452Q can be configured to transition between sample rates (with their respective current consumption) based on four of the interrupt functions of the device. The advantage of using the Auto-WAKE/SLEEP is that the system can automatically transition to a higher sample rate (higher current consumption) when needed but spends the majority of the time in the SLEEP mode (lower current) when the device does not require higher sampling rates. Auto-WAKE refers to the device being triggered by one of the interrupt functions to transition to a higher sample rate. This may also interrupt the processor to transition from a SLEEP mode to a higher power mode.

SLEEP mode occurs after the accelerometer has not detected an interrupt for longer than the user definable time-out period. The device will transition to the specified lower sample rate. It may also alert the processor to go into a lower power mode to save on current during this period of inactivity.

The Interrupts that can WAKE the device from SLEEP are the following: Tap Detection, Orientation Detection, Motion/Freefall, and Transient Detection. Refer to AN4074, for more detailed information for configuring the Auto-WAKE/SLEEP.

5.5 Freefall and Motion Detection

MMA8452Q has flexible interrupt architecture for detecting either a Freefall or a Motion. Freefall can be enabled where the set threshold must be less than the configured threshold, or motion can be enabled where the set threshold must be greater than the threshold. The motion configuration has the option of enabling or disabling a high pass filter to eliminate tilt data (static offset). The freefall does not use the high pass filter. For details on the Freefall and Motion detection with specific application examples and recommended configuration settings, refer to Freescale application note AN4070.

5.5.1 Freefall Detection

The detection of "Freefall" involves the monitoring of the X, Y, and Z axes for the condition where the acceleration magnitude is **below** a user specified threshold for a user definable amount of time. Normally the usable threshold ranges are between ±100 mg and ±500 mg.

5.5.2 Motion Detection

Motion is often used to simply alert the main processor that the device is currently in use. When the acceleration exceeds a set threshold the motion interrupt is asserted. A motion can be a fast moving shake or a slow moving tilt. This will depend on the threshold and timing values configured for the event. The motion detection function can analyze static acceleration changes or faster jolts. For example, to detect that an object is spinning, all three axes would be enabled with a threshold detection of $> 2q$. This condition would need to occur for a minimum of 100 ms to ensure that the event wasn't just noise. The timing value is set by a configurable debounce counter. The debounce counter acts like a filter to determine whether the condition exists for configurable set of time (i.e., 100 ms or longer). There is also directional data available in the source register to detect the direction of the motion. This is useful for applications such as directional shake or flick, which assists with the algorithm for various gesture detections.

5.6 Transient Detection

The MMA8452Q has a built-in high pass filter. Acceleration data goes through the high pass filter, eliminating the offset (DC) and low frequencies. The high pass filter cut-off frequency can be set by the user to four different frequencies which are dependent on the Output Data Rate (ODR). A higher cut-off frequency ensures the DC data or slower moving data will be filtered out, allowing only the higher frequencies to pass. The embedded Transient Detection function uses the high pass filtered data allowing the user to set the threshold and debounce counter. The Transient detection feature can be used in the same manner as the motion detection by bypassing the high pass filter. There is an option in the configuration register to do this. This adds more flexibility to cover various customer use cases.

Many applications use the accelerometer's static acceleration readings (i.e., tilt) which measure the change in acceleration due to gravity only. These functions benefit from acceleration data being filtered with a low pass filter where high frequency data is considered noise. However, there are many functions where the accelerometer must analyze dynamic acceleration. Functions such as tap, flick, shake and step counting are based on the analysis of the change in the acceleration. It is simpler to interpret these functions dependent on dynamic acceleration data when the static component has been removed. The Transient Detection function can be routed to either interrupt pin through bit 5 in CTRL_REG5 register (0x2E). Registers 0x1D – 0x20 are the dedicated Transient Detection configuration registers. The source register contains directional data to determine the direction of the acceleration, either positive or negative. For details on the benefits of the embedded Transient Detection function along with specific application examples and recommended configuration settings, please refer to Freescale application note, AN4071.

5.7 Tap Detection

The MMA8452Q has embedded single/double and directional tap detection. This function has various customizing timers for setting the pulse time width and the latency time between pulses. There are programmable thresholds for all three axes. The tap detection can be configured to run through the high pass filter and also through a low pass filter, which provides more customizing and tunable tap detection schemes. The status register provides updates on the axes where the event was detected and the direction of the tap. For more information on how to configure the device for tap detection please refer to Freescale application note AN4072.

5.8 Orientation Detection

The MMA8452Q has an orientation detection algorithm with the ability to detect all 6 orientations. The transition from portrait to landscape is fixed with a 45° threshold angle and $a \pm 14$ ° hy steresis angle. This allows the for a smooth transition from portrait to landscape at approximately 30° and then fr om landscape to portrait at approximately 60°.

The angle at which the device no longer detects the orientation change is referred to as the "Z-Lockout angle". The device operates down to 29° from the flat posit ion. All angles are accurate to $\pm 2^{\circ}$.

For further information on the orientation detection function refer to Freescale application note, AN4068.

[Figure 8](#page-13-0) and [Figure 9](#page-13-1) show the definitions of the trip angles going from Landscape to Portrait and then also from Portrait to Landscape.

Figure 7. Landscape/Portrait Orientation

[Figure 10](#page-13-2) illustrates the Z-angle lockout region. When lifting the device upright from the flat position it will be active for orientation detection as low as 29° from flat. .

Figure 10. Illustration of Z-Tilt Angle Lockout Transition

5.9 Interrupt Register Configurations

There are six configurable interrupts in the MMA8452Q: Data Ready, Motion/Freefall, Tap (Pulse), Orientation, Transient, and Auto-SLEEP events. These six interrupt sources can be routed to one of two interrupt pins. The interrupt source must be enabled and configured. If the event flag is asserted because the event condition is detected, the corresponding interrupt pin, INT1 or INT2, will assert.

Figure 11. System Interrupt Generation Block Diagram

5.10 Serial I2C Interface

Acceleration data may be accessed through an I²C interface thus making the device particularly suitable for direct interfacing with a microcontroller. The MMA8452Q features an interrupt signal which indicates when a new set of measured acceleration data is available thus simplifying data synchronization in the digital system that uses the device. The MMA8452Q may also be configured to generate other interrupt signals accordingly to the programmable embedded functions of the device for Motion, Freefall, Transient, Orientation, and Tap.

The registers embedded inside the MMA8452Q are accessed through the I^2C serial interface [\(Table 8](#page-14-2)). To enable the I^2C interface, VDDIO line must be tied high (i.e., to the interface supply voltage). If VDD is not present and VDDIO is present, the MMA8452Q is in off mode and communications on the I^2C interface are ignored. The I^2C interface may be used for communications between other I^2C devices and the MMA8452Q does not affect the I^2C bus.

Table 8. Serial Interface Pin Description

There are two signals associated with the I^2C bus; the Serial Clock Line (SCL) and the Serial Data line (SDA). The latter is a bidirectional line used for sending and receiving the data to/from the interface. External pullup resistors connected to VDDIO are expected for SDA and SCL. When the bus is free both the lines are high. The $1²C$ interface is compliant with fast mode (400 kHz), and Normal mode (100 kHz) 1^2C standards ([Table 4\)](#page-7-2).

5.10.1 I2C Operation

The transaction on the bus is started through a start condition (START) signal. START condition is defined as a HIGH to LOW transition on the data line while the SCL line is held HIGH. After START has been transmitted by the Master, the bus is considered busy. The next byte of data transmitted after START contains the slave address in the first 7 bits, and the eighth bit tells whether the Master is receiving data from the slave or transmitting data to the slave. When an address is sent, each device in the system compares the first seven bits after a start condition with its address. If they match, the device considers itself addressed by the Master. The 9th clock pulse, following the slave address byte (and each subsequent byte) is the acknowledge (ACK). The transmitter must release the SDA line during the ACK period. The receiver must then pull the data line low so that it remains stable low during the high period of the acknowledge clock period.

A LOW to HIGH transition on the SDA line while the SCL line is high is defined as a stop condition (STOP). A data transfer is always terminated by a STOP. A Master may also issue a repeated START during a data transfer. The MMA8452Q expects repeated STARTs to be used to randomly read from specific registers.

The MMA8452Q's standard slave address is a choice between the two sequential addresses 0011100 and 0011101. The selection is made by the high and low logic level of the SA0 (pin 7) input respectively. The slave addresses are factory programmed and alternate addresses are available at customer request. The format is shown in [Table 9.](#page-15-1)

Table 9. I2C Address Selection Table

Single Byte Read

The MMA8452Q has an internal ADC that can sample, convert and return sensor data on request. The transmission of an 8-bit command begins on the falling edge of SCL. After the eight clock cycles are used to send the command, note that the data returned is sent with the MSB first once the data is received. [Figure 12](#page-16-0) shows the timing diagram for the accelerometer 8-bit ${}^{12}C$ read operation. The Master (or MCU) transmits a start condition (ST) to the MMA8452Q, slave address (\$1D), with the R/W bit set to "0" for a write, and the MMA8452Q sends an acknowledgement. Then the Master (or MCU) transmits the address of the register to read and the MMA8452Q sends an acknowledgement. The Master (or MCU) transmits a repeated start condition (SR) and then addresses the MMA8452Q (\$1D) with the R/W bit set to "1" for a read from the previously selected register. The Slave then acknowledges and transmits the data from the requested register. The Master does not acknowledge (NAK) the transmitted data, but transmits a stop condition to end the data transfer.

Multiple Byte Read

When performing a multi-byte read or "burst read", the MMA8452Q automatically increments the received register address commands after a read command is received. Therefore, after following the steps of a single byte read, multiple bytes of data can be read from sequential registers after each MMA8452Q acknowledgment (AK) is received until a no acknowledge (NAK) occurs from the Master followed by a stop condition (SP) signaling an end of transmission.

Single Byte Write

To start a write command, the Master transmits a start condition (ST) to the MMA8452Q, slave address (\$1D) with the R/W bit set to "0" for a write, the MMA8452Q sends an acknowledgement. Then the Master (MCU) transmits the address of the register to write to, and the MMA8452Q sends an acknowledgement. Then the Master (or MCU) transmits the 8-bit data to write to the designated register and the MMA8452Q sends an acknowledgement that it has received the data. Since this transmission is complete, the Master transmits a stop condition (SP) to the data transfer. The data sent to the MMA8452Q is now stored in the appropriate register.

Multiple Byte Write

The MMA8452Q automatically increments the received register address commands after a write command is received. Therefore, after following the steps of a single byte write, multiple bytes of data can be written to sequential registers after each MMA8452Q acknowledgment (ACK) is received.

Table 10. I2C Device Address Sequence

< Single Byte Read >

< Multiple Byte Read >

< Single Byte Write >

< Multiple Byte Write >

6 Register Descriptions

Table 11. Register Address Map

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Table 11. Register Address Map

1. Register contents are preserved when transition from ACTIVE to STANDBY mode occurs.

2. Register contents are reset when transition from STANDBY to ACTIVE mode occurs.

3. Modification of this register's contents can only occur when device is STANDBY mode except CTRL_REG1 ACTIVE bit and CTRL_REG2 RST bit.

Note: Auto-increment addresses which are not a simple increment are highlighted in **bold**. The auto-increment addressing is only enabled when device registers are read using I²C burst read mode. Therefore the internal storage of the auto-increment address is cleared whenever a stop-bit is detected.

6.1 Data Registers

The following are the data registers for the MMA8452Q. For more information on data manipulation of the MMA8452Q, refer to application note, AN4076.

0x00 STATUS: Data Status Register (Read Only)

Table 12. STATUS Description

ZYXOW is set whenever a new acceleration data is produced before completing the retrieval of the previous set. This event occurs when the content of at least one acceleration data register (i.e., OUT_X, OUT_Y, OUT_Z) has been overwritten. ZYXOW is cleared when the high-bytes of the acceleration data (OUT_X_MSB, OUT_Y_MSB, OUT_Z_MSB) of all the active channels are read.

ZOW is set whenever a new acceleration sample related to the Z-axis is generated before the retrieval of the previous sample. When this occurs the previous sample is overwritten. ZOW is cleared anytime OUT_Z_MSB register is read.

YOW is set whenever a new acceleration sample related to the Y-axis is generated before the retrieval of the previous sample. When this occurs the previous sample is overwritten. YOW is cleared anytime OUT_Y_MSB register is read.

XOW is set whenever a new acceleration sample related to the X-axis is generated before the retrieval of the previous sample. When this occurs the previous sample is overwritten. XOW is cleared anytime OUT_X_MSB register is read.

ZYXDR signals that a new sample for any of the enabled channels is available. ZYXDR is cleared when the high-bytes of the acceleration data (OUT_X_MSB, OUT_Y_MSB, OUT_Z_MSB) of all the enabled channels are read.

ZDR is set whenever a new acceleration sample related to the Z-axis is generated. ZDR is cleared anytime OUT_Z_MSB register is read.

YDR is set whenever a new acceleration sample related to the Y-axis is generated. YDR is cleared anytime OUT_Y_MSB register is read.

XDR is set whenever a new acceleration sample related to the X-axis is generated. XDR is cleared anytime OUT_X_MSB register is read.

Data Registers: 0x01 OUT_X_MSB, 0x02 OUT_X_LSB, 0x03 OUT_Y_MSB, 0x04 OUT_Y_LSB, 0x05 OUT_Z_MSB, 0x06 OUT_Z_LSB

These registers contain the X-axis, Y-axis, and Z-axis 12-bit output sample data expressed as 2's complement numbers. The sample data output registers store the current sample data.

0x01 OUT_X_MSB: X_MSB Register (Read Only)

0x05 OUT_Z_MSB: Z_MSB Register (Read Only)

0x06 OUT_Z_LSB: Z_LSB Register (Read Only)

OUT_X_MSB, OUT_X_LSB, OUT_Y_MSB, OUT_Y_LSB, OUT_Z_MSB, and OUT_Z_LSB are stored in the autoincrementing address range of 0x01 to 0x06 to reduce reading the status followed by 12-bit axis data to 7 bytes. If the F_READ bit is set (0x2A bit 1), auto increment will skip over LSB registers. This will shorten the data acquisition from 7 bytes to 4 bytes. The LSB registers can only be read immediately following the read access of the corresponding MSB register. A random read access to the LSB registers is not possible. Reading the MSB register and then the LSB register in sequence ensures that both bytes (LSB and MSB) belong to the same data sample, even if a new data sample arrives between reading the MSB and the LSB byte.

0x0B: SYSMOD System Mode Register

The system mode register indicates the current device operating mode. Applications using the Auto-SLEEP/WAKE mechanism should use this register to synchronize the application with the device operating mode transitions.

0x0B SYSMOD: System Mode Register (Read Only)

Table 13. SYSMOD Description

0x0C: INT_SOURCE System Interrupt Status Register

In the interrupt source register the status of the various embedded features can be determined. The bits that are set (logic '1') indicate which function has asserted an interrupt and conversely the bits that are cleared (logic '0') indicate which function has not asserted or has deasserted an interrupt. **The bits are set by a low to high transition and are cleared by reading the appropriate interrupt source register.** The SRC_DRDY bit is cleared by reading the X, Y and Z data. It is not cleared by simply reading the Status Register (0x00).

0x0C INT_SOURCE: System Interrupt Status Register (Read Only)

Table 14. INT_SOURCE Description

0x0D: WHO_AM_I Device ID Register

The device identification register identifies the part. The default value is 0x2A. This value is factory programmed. Consult the factory for custom alternate values.

0x0D: WHO_AM_I Device ID Register (Read Only)

0x0E: XYZ_DATA_CFG Register

The XYZ_DATA_CFG register sets the dynamic range and sets the high pass filter for the output data. When the HPF_OUT bit is set. The data registers 0x01 - 0x06 will contain high pass filtered data when this bit is set.

0x0E: XYZ_DATA_CFG (Read/Write)

Table 15. XYZ Data Configuration Descriptions

The default full scale value range is 2g and the high pass filter is disabled.

Table 16. Full Scale Range

0x0F: HP_FILTER_CUTOFF High Pass Filter Register

This register sets the high-pass filter cut-off frequency for removal of the offset and slower changing acceleration data. The output of this filter is indicated by the data registers (0x01-0x06) when bit 4 (HPF_OUT) of Register 0x0E is set. The filter cut-off options change based on the data rate selected as shown in [Table 18.](#page-23-1) For details of implementation on the high pass filter, refer to Freescale application note AN4071.

0x0F HP_FILTER_CUTOFF: High Pass Filter Register (Read/Write)

Table 17. High Pass Filter Cut-off Register Descriptions

Table 18. High Pass Filter Cut-off Options

6.2 Portrait/ Landscape Embedded Function Registers

For more details on the meaning of the different user configurable settings and for example code refer to Freescale application note AN4068.

0x10: PL_STATUS Portrait/Landscape Status Register

This status register can be read to get updated information on any change in orientation by reading Bit 7, or on the specifics of the orientation by reading the other bits. For further understanding of Portrait Up, Portrait Down, Landscape Left, Landscape Right, Back and Front orientations please refer to [Figure 3.](#page-3-0) The interrupt is cleared when reading the PL_STATUS register.

Table 19. PL_STATUS Register Description

1. The default power up state is $BAFRO = 0$, $LAPO = 0$, and $LO = 0$.

NEWLP is set to 1 after the first orientation detection after a STANDBY to ACTIVE transition, and whenever a change in LO, BAFRO, or LAPO occurs. NEWLP bit is cleared anytime PL_STATUS register is read. The Orientation mechanism state change is limited to a maximum 1.25g. LAPO BAFRO and LO continue to change when NEWLP is set. The current position is locked if the absolute value of the acceleration experienced on any of the three axes is greater than 1.25g.

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0x11 Portrait/Landscape Configuration Register

This register enables the Portrait/Landscape function and sets the behavior of the debounce counter.

0x11 PL_CFG Register (Read/Write)

Table 20. PL_CFG Description

0x12 Portrait/Landscape Debounce Counter

This register sets the debounce count for the orientation state transition. The minimum debounce latency is determined by the data rate set by the product of the selected system ODR and PL_COUNT registers. Any transition from WAKE to SLEEP or vice versa resets the internal Landscape/Portrait debounce counter. **Note:** The debounce counter weighting (time step) changes based on the ODR and the Oversampling mode. [Table 22](#page-24-0) explains the time step value for all sample rates and all Oversampling modes.

0x12 PL_COUNT Register (Read/Write)

Table 21. PL_COUNT Description

DBCNE[7:0] Debounce Count value. Default value: 0000_0000.

Table 22. PL_COUNT Relationship with the ODR

0x13: PL_BF_ZCOMP Back/Front and Z Compensation Register

The Z-Lock angle compensation is set to 29°. The Back to Front trip angle is set to ±75°.

0x13: PL_BF_ZCOMP Register (Read Only)

Table 23. PL_BF_ZCOMP Description

Note: All angles are accurate to ±2°.

0x14: P_L_THS_REG Portrait/Landscape Threshold and Hysteresis Register

This register represents the Portrait to Landscape trip threshold.

0x14: P_L_THS_REG Register (Read Only)

Table 24. P_L_THS_REG Description

Table 25. Trip Angles with Hysteresis for 45° Angle

6.3 Motion and Freefall Embedded Function Registers

The freefall/motion function can be configured in either freefall or motion detection mode via the **OAE** configuration bit (0x15 bit 6). The freefall/motion detection block can be disabled by setting all three bits ZEFE, YEFE, and XEFE to zero.

Depending on the register bits **ELE** (0x15 bit 7) and **OAE** (0x15 bit 6), each of the freefall and motion detection block can operate in four different modes:

Mode 1: Freefall Detection with ELE = 0, OAE = 0

In this mode, the **EA** bit (0x16 bit 7) indicates a freefall event after the debounce counter is complete. The ZEFE, YEFE, and XEFE control bits determine which axes are considered for the freefall detection. Once the EA bit is set, and DBCNTM = 0, the EA bit can get cleared only after the delay specified by FF_MT_COUNT. This is because the counter is in decrement mode. If DBCNTM = 1, the EA bit is cleared as soon as the freefall condition disappears, and will not be set again before the delay specified by FF_MT_COUNT has passed. Reading the FF_MT_SRC register does not clear the EA bit. The event flags (0x16) ZHE, ZHP, YHE, YHP, XHE, and XHP reflect the motion detection status (i.e. high g event) without any debouncing, provided that the corresponding bits ZEFE, YEFE, and/or XEFE are set.

Mode 2: Freefall Detection with ELE = 1, OAE = 0

In this mode, the **EA** event bit indicates a freefall event after the debounce counter. Once the debounce counter reaches the time value for the set threshold, the EA bit is set, and remains set until the FF_MT_SRC register is read. When the FF_MT_SRC register is read, the EA bit and the debounce counter are cleared and a new event can only be generated after the delay specified by FF_MT_CNT. The ZEFE, YEFE, and XEFE control bits determine which axes are considered for the freefall detection. While EA = 0, the event flags ZHE, ZHP, YHE, YHP, XHE, and XHP reflect the motion detection status (i.e., high g event) without any debouncing, provided that the corresponding bits ZEFE, YEFE, and/or XEFE are set. The event flags ZHE, ZHP, YHE, YHP, XHE, and XHP are latched when the EA event bit is set. The event flags ZHE, ZHP, YHE, YHP, XHE, and XHP will start changing only after the FF_MT_SRC register has been read.

Mode 3: Motion Detection with ELE = 0, OAE = 1

In this mode, the **EA** bit indicates a motion event after the debounce counter time is reached. The ZEFE, YEFE, and XEFE control bits determine which axes are taken into consideration for motion detection. Once the **EA** bit is set, and DBCNTM = 0, the EA bit can get cleared only after the delay specified by FF_MT_COUNT. If DBCNTM = 1, the **EA** bit is cleared as soon as the motion high g condition disappears. The event flags ZHE, ZHP, YHE, YHP, XHE, and XHP reflect the motion detection status (i.e., high g event) without any debouncing, provided that the corresponding bits ZEFE, YEFE, and/or XEFE are set. Reading the FF_MT_SRC does not clear any flags, nor is the debounce counter reset.

Mode 4: Motion Detection with ELE = 1, OAE = 1

In this mode, the EA bit indicates a motion event after debouncing. The ZEFE, YEFE, and XEFE control bits determine which axes are taken into consideration for motion detection. Once the debounce counter reaches the threshold, the EA bit is set, and remains set until the FF_MT_SRC register is read. When the FF_MT_SRC register is read, all register bits are cleared and the debounce counter are cleared and a new event can only be generated after the delay specified by FF_MT_CNT. While the bit EA is zero, the event flags ZHE, ZHP, YHE, YHP, XHE, and XHP reflect the motion detection status (i.e., high g event) without any debouncing, provided that the corresponding bits ZEFE, YEFE, and/or XEFE are set. When the EA bit is set, these bits keep their current value until the FF_MT_SRC register is read.

0x15 FF_MT_CFG Freefall/Motion Configuration Register

This is the Freefall/Motion configuration register for setting up the conditions of the freefall or motion function.

0x15 FF_MT_CFG Register (Read/Write)

Table 26. FF_MT_CFG Description

OAE bit allows the selection between Motion (logical OR combination) and Freefall (logical AND combination) detection. **ELE** denotes whether the enabled event flag will to be latched in the FF_MT_SRC register or the event flag status in the

FF_MT_SRC will indicate the real-time status of the event. If ELE bit is set to a logic '1', then the event flags are frozen when the EA bit gets set, and are cleared by reading the FF_MT_SRC source register.

ZHFE, YEFE, XEFE enable the detection of a motion or freefall event when the measured acceleration data on X, Y, Z channel is beyond the threshold set in FF_MT_THS register. If the ELE bit is set to logic '1' in the FF_MT_CFG register new event flags are blocked from updating the FF_MT_SRC register.

FF_MT_THS is the threshold register used to detect freefall motion events. The unsigned 7-bit **FF_MT_THS** threshold register holds the threshold for the freefall detection where the magnitude of the X and Y and Z acceleration values is lower or equal than the threshold value. Conversely, the **FF_MT_THS** also holds the threshold for the motion detection where the magnitude of the X or Y or Z acceleration value is higher than the threshold value.

Figure 13. FF_MT_CFG High and Low g Level

0x16 FF_MT_SRC Freefall/Motion Source Register

0x16: FF_MT_SRC Freefall and Motion Source Register (Read Only)

Table 27. Freefall/Motion Source Description

	Event Active Flag. Default value: 0.				
EA	0: No event flag has been asserted; 1: one or more event flag has been asserted.				
	See the description of the OAE bit to determine the effect of the 3-axis event flags on the EA bit.				
ZHE	Z Motion Flag. Default value: 0.				
	0: No Z Motion event detected, 1: Z Motion has been detected				
	This bit reads always zero if the ZEFE control bit is set to zero				
ZHP	Z Motion Polarity Flag. Default value: 0.				
	0: Z event was Positive g, 1: Z event was Negative g				
	This bit read always zero if the ZEFE control bit is set to zero				
YHE	Y Motion Flag. Default value: 0.				
	0: No Y Motion event detected, 1: Y Motion has been detected				
	This bit read always zero if the YEFE control bit is set to zero				
YHP	Y Motion Polarity Flag. Default value: 0				
	0: Y event detected was Positive g, 1: Y event was Negative g				
	This bit reads always zero if the YEFE control bit is set to zero				
XHE	X Motion Flag. Default value: 0				
	0: No X Motion event detected, 1: X Motion has been detected				
	This bit reads always zero if the XEFE control bit is set to zero				
XHP	X Motion Polarity Flag. Default value: 0				
	0: X event was Positive g, 1: X event was Negative g				
	This bit reads always zero if the XEFE control bit is set to zero				

This register keeps track of the acceleration event which is triggering (or has triggered, in case of ELE bit in FF_MT_CFG register being set to 1) the event flag. In particular EA is set to a logic '1' when the logical combination of acceleration events flags specified in FF_MT_CFG register is true. This bit is used in combination with the values in INT_EN_FF_MT and INT_CFG_FF_MT register bits to generate the freefall/motion interrupts.

An X,Y, or Z motion is true when the acceleration value of the X or Y or Z channel is higher than the preset threshold value defined in the FF_MT_THS register.

Conversely an X, Y, and Z low event is true when the acceleration value of the X and Y and Z channel is lower than or equal to the preset threshold value defined in the FF_MT_THS register.

0x17: FF_MT_THS Freefall and Motion Threshold Register

0x17 FF_MT_THS Register (Read/Write)

Table 28. FF_MT_THS Description

The threshold resolution is 0.063g/LSB and the threshold register has a range of 0 to 127 counts. The maximum range is to 8g. Note that even when the full scale value is set to 2g or 4g the motion detects up to 8g. If the Low Noise bit is set in Register 0x2A then the maximum threshold will be limited to 4g regardless of the full scale range.

DBCNTM bit configures the way in which the debounce counter is reset when the inertial event of interest is momentarily not true.

When DBCNTM bit is a logic '1', the debounce counter is cleared to 0 whenever the inertial event of interest is no longer true as shown in [Figure 14](#page-29-0), (b). While the DBCNTM bit is set to logic '0' the debounce counter is decremented by 1 whenever the inertial event of interest is no longer true ([Figure 14,](#page-29-0) (c)) until the debounce counter reaches 0 or the inertial event of interest becomes active.

Decrementing the debounce counter acts as a median enabling the system to filter out irregular spurious events which might impede the detection of inertial events.

0x18 FF_MT_COUNT Debounce Register

This register sets the number of debounce sample counts for the event trigger.

0x18 FF_MT_COUNT_Register (Read/Write)

Table 29. FF_MT_COUNT Description

This register sets the minimum number of debounce sample counts of continuously matching the detection condition user selected for the freefall, motion event.

When the internal debounce counter reaches the FF_MT_COUNT value a Freefall/Motion event flag is set. The debounce counter will never increase beyond the FF_MT_COUNT value. Time step used for the debounce sample count depends on the ODR chosen and the Oversampling mode as shown in [Table 30.](#page-28-0)

Table 30. FF_MT_COUNT Relationship with the ODR

Figure 14. DBCNTM Bit Function

6.4 Transient (HPF) Acceleration Detection

For more information on the uses of the transient function please review application note AN4071. This function is similar to the motion detection except that high pass filtered data is compared. There is an option to disable the high pass filter through the function. In this case the behavior is the same as the motion detection. This allows for the device to have 2 motion detection functions.

0x1D: Transient_CFG Register

The transient detection mechanism can be configured to raise an interrupt when the magnitude of the high pass filtered acceleration threshold is exceeded. The TRANSIENT_CFG register is used to enable the transient interrupt generation mechanism for the 3 axes (X, Y, Z) of acceleration. There is also an option to bypass the high pass filter. When the high pass filter is bypassed, the function behaves similar to the motion detection.

0x1D TRANSIENT_CFG Register (Read/Write)

Table 31. TRANSIENT_CFG Description

0x1E TRANSIENT_SRC Register

The Transient Source register provides the status of the enabled axes and the polarity (directional) information. When this register is read it clears the interrupt for the transient detection. When new events arrive while EA = 1, additional *TRANSE bits may get set, and the corresponding *_Trans_Pol flag become updated. However no *TRANSE bit may get cleared before the TRANSIENT_SRC register is read.

0x1E TRANSIENT_SRC Register (Read Only)

Table 32. TRANSIENT_SRC Description

When the EA bit gets set while ELE = 1, all other status bits get frozen at their current state. By reading the TRANSIENT_SRC register, all bits get cleared.

0x1F TRANSIENT_THS Register

The Transient Threshold register sets the threshold limit for the detection of the transient acceleration. The value in the TRANSIENT_THS register corresponds to a g value which is compared against the values of High Pass Filtered Data. If the High Pass Filtered acceleration value exceeds the threshold limit an event flag is raised and the interrupt is generated if enabled.

0x1F TRANSIENT_THS Register (Read/Write)

Table 33. TRANSIENT_THS Description

The threshold THS[6:0] is a 7-bit unsigned number, 0.063g/LSB. The maximum threshold is 8g. Even if the part is set to full scale at 2g or 4g this function will still operate up to 8g. If the Low Noise bit is set in Register 0x2A the maximum threshold to be reached is 4g.

0x20 TRANSIENT_COUNT

The TRANSIENT_COUNT sets the minimum number of debounce counts continuously matching the condition where the unsigned value of high pass filtered data is greater than the user specified value of TRANSIENT_THS.

0x20 TRANSIENT_COUNT Register (Read/Write)

Table 34. TRANSIENT_COUNT Description

D[7:0] Count value. Default value: 0000_0000.

The time step for the transient detection debounce counter is set by the value of the system ODR and the Oversampling mode.

Table 35. TRANSIENT_COUNT Relationship with the ODR

6.5 Single, Double and Directional Tap Detection Registers

For more details of how to configure the tap detection and sample code please refer to Freescale application note, AN4072. The tap detection registers are referred to as "Pulse".

0x21: PULSE_CFG Pulse Configuration Register

This register configures the event flag for the tap detection for enabling/disabling the detection of a single and double pulse on each of the axes.

0x21 PULSE_CFG Register (Read/Write)

Table 36. PULSE_CFG Description

0x22: PULSE_SRC Pulse Source Register

This register indicates a double or single pulse event has occurred and also which direction. The corresponding axis and event must be enabled in Register 0x21 for the event to be seen in the source register.

0x22 PULSE_SRC Register (Read Only)

Table 37. PULSE_SRC Description

When the EA bit gets set while ELE = 1, all status bits (AxZ, AxY, AxZ, DPE, and PolX, PolY, PolZ) are frozen. Reading the PULSE_SRC register clears all bits. Reading the source register will clear the interrupt.

0x23 - 0x25: PULSE_THSX, Y, Z Pulse Threshold for X, Y & Z Registers

The pulse threshold can be set separately for the X, Y and Z axes. The PULSE_THSX, PULSE_THSY and PULSE_THSZ registers define the threshold which is used by the system to start the pulse detection procedure.

0x23 PULSE_THSX Register (Read/Write)

Table 38. PULSE_THSX Description

0x24 PULSE_THSY Register (Read/Write)

Table 39. PULSE_THSY Description

0x25 PULSE_THSZ Register (Read/Write)

Table 40. PULSE_THSZ Description

The threshold values range from 1 to 127 with steps of 0.63g/LSB at a fixed 8g acceleration range, thus the minimum resolution is always fixed at 0.063g/LSB. If the Low Noise bit in Register 0x2A is set then the maximum threshold will be 4g. The PULSE_THSX, PULSE_THSY and PULSE_THSZ registers define the threshold which is used by the system to start the pulse detection procedure. The threshold value is expressed over 7-bits as an unsigned number.

0x26: PULSE_TMLT Pulse Time Window 1 Register

0x26 PULSE_TMLT Register (Read/Write)

Table 41. PULSE_TMLT Description

The bits TMLT7 through TMLT0 define the maximum time interval that can elapse between the start of the acceleration on the selected axis exceeding the specified threshold and the end when the acceleration on the selected axis must go below the specified threshold to be considered a valid pulse.

The minimum time step for the pulse time limit is defined in [Table 42](#page-33-0) and [Table 43.](#page-34-0) Maximum time for a given ODR and Oversampling mode is the time step pulse multiplied by 255. The time steps available are dependent on the Oversampling mode and whether the Pulse Low Pass Filter option is enabled or not. The Pulse Low Pass Filter is set in Register 0x0F.

Table 42. Time Step for PULSE Time Limit (Reg 0x0F) Pulse_LPF_EN = 1

Table 43. Time Step for PULSE Time Limit (Reg 0x0F) Pulse_LPF_EN = 0

0x27: PULSE_LTCY Pulse Latency Timer Register

0x27 PULSE_LTCY Register (Read/Write)

Table 44. PULSE_LTCY Description

The bits LTCY7 through LTCY0 define the time interval that starts after the first pulse detection. During this time interval, all pulses are ignored. **Note:** This timer must be set for single pulse and for double pulse.

The minimum time step for the pulse latency is defined in [Table 45](#page-34-1) and [Table 46](#page-34-2). The maximum time is the time step at the ODR and Oversampling mode multiplied by 255. The timing also changes when the Pulse LPF is enabled or disabled.

Table 45. Time Step for PULSE Latency @ ODR and Power Mode (Reg 0x0F) Pulse_LPF_EN = 1

0x28 PULSE_WIND Register (Read/Write)

0x28: PULSE_WIND Second Pulse Time Window Register

Table 47. PULSE_WIND Description

The bits WIND7 through WIND0 define the maximum interval of time that can elapse after the end of the latency interval in which the start of the second pulse event must be detected provided the device has been configured for double pulse detection. The detected second pulse width must be shorter than the time limit constraints specified by the PULSE_TMLT register, but the end of the double pulse need not finish within the time specified by the PULSE_WIND register.

The minimum time step for the pulse window is defined in [Table 48](#page-35-0) and [Table 49](#page-35-1). The maximum time is the time step at the ODR, Oversampling mode and LPF Filter Option multiplied by 255.

Table 48. Time Step for PULSE Detection Window @ ODR and Power Mode (Reg 0x0F) Pulse_LPF_EN = 1

6.6 Auto-WAKE/SLEEP Detection

The ASLP_COUNT register sets the minimum time period of inactivity required to change current ODR value from the value specified in the **DR[2:0]** register to **ASLP_RATE** register value, provided the **SLPE** bit is set to a logic '1' in the **CTRL_REG2** register. See [Table 45](#page-34-1) for functional blocks that may be monitored for inactivity in order to trigger the "return to SLEEP" event.

0x29 ASLP_COUNT Register (Read/Write)

Table 50. ASLP_COUNT Description

D7-D0 defines the minimum duration time to change current ODR value from **DR** to **ASLP_RATE**. Time step and maximum value depend on the ODR chosen as shown in [Table 51.](#page-36-1)

Table 52. SLEEP/WAKE Mode Gates and Triggers

In order to wake the device, the desired function or functions must be enabled in CTRL_REG4 and set to WAKE to SLEEP in CTRL_REG3. All enabled functions will still function in SLEEP mode at the SLEEP ODR. Only the functions that have been selected for WAKE from SLEEP will **WAKE** the device.

MMA8452Q has 4 functions that can be used to keep the sensor from falling asleep namely, Transient, Orientation, Tap, and Motion/FF. One or more of these functions can be enabled. In order to WAKE the device, 4 functions are provided namely, Transient, Orientation, Tap, and the Motion/Freefall. The Auto-WAKE/SLEEP interrupt does not affect the WAKE/SLEEP, nor does the data ready interrupt. See Register 0x2C for the WAKE from SLEEP bits.

If the Auto-SLEEP bit is disabled, then the device can only toggle between STANDBY and WAKE mode. If Auto-SLEEP interrupt is enabled, transitioning from ACTIVE mode to Auto-SLEEP mode and vice versa generates an interrupt.

6.7 Control Registers

Note: Except for STANDBY mode selection, the device must be in STANDBY mode to change any of the fields within CTRL_REG1 (0X2A).

0x2A: CTRL_REG1 System Control 1 Register

0x2A CTRL_REG1 Register (Read/Write)

Table 53. CTRL_REG1 Description

Table 54. SLEEP Mode Rate Description

It is important to note that when the device is Auto-SLEEP mode, the system ODR and the data rate for all the system functional blocks are overridden by the data rate set by the **ASLP_RATE** field.

DR[2:0] bits select the Output Data Rate (ODR) for acceleration samples. The default value is 000 for a data rate of 800 Hz.

Table 55. System Output Data Rate Selection

ACTIVE bit selects between STANDBY mode and ACTIVE mode. The default value is 0 for STANDBY mode.

Table 56. Full Scale Selection

LNoise bit selects between normal full dynamic range mode and a high sensitivity, Low Noise mode. In Low Noise mode the maximum signal that can be measured is ±4g. **Note:** Any thresholds set above 4g will not be reached.

F_Read bit selects between Normal and Fast Read mode. When selected, the auto increment counter will skip over the LSB data bytes.

0x2B: CTRL_REG2 System Control 2 Register

0x2B CTRL_REG2 Register (Read/Write)

Table 57. CTRL_REG2 Description

ST bit activates the self-test function. When ST is set, X, Y, and Z outputs will shift. **RST** bit is used to activate the software reset. The reset mechanism can be enabled in STANDBY and ACTIVE mode.

When the reset bit is enabled, all registers are rest and are loaded with default values. Writing '1' to the RST bit immediately resets the device, no matter whether it is in ACTIVE/WAKE, ACTIVE/SLEEP, or STANDBY mode.

The I^2C communication system is reset to avoid accidental corrupted data access.

At the end of the boot process the RST bit is deasserted to 0. Reading this bit will return a value of zero.

The **(S)MODS[1:0]** bits select which Oversampling mode is to be used shown in [Table 58](#page-38-0). The Oversampling modes are available in both WAKE Mode MOD[1:0] and also in the SLEEP Mode SMOD[1:0].

Table 58. MODS Oversampling Modes

0x2C: CTRL_REG3 Interrupt Control Register

0x2C CTRL_REG3 Register (Read/Write)

Table 60. CTRL_REG3 Description

IPOL bit selects the polarity of the interrupt signal. When IPOL is '0' (default value) any interrupt event will signaled with a logical 0.

PP_OD bit configures the interrupt pin to Push-Pull or in Open Drain mode. The default value is 0 which corresponds to Push-Pull mode. The Open Drain configuration can be used for connecting multiple interrupt signals on the same interrupt line.

0x2D: CTRL_REG4 Register (Read/Write)

0x2D CTRL_REG4 Register (Read/Write)

Table 61. Interrupt Enable Register Description

The corresponding functional block interrupt enable bit allows the functional block to route its event detection flags to the system's interrupt controller. The interrupt controller routes the enabled functional block interrupt to the INT1 or INT2 pin.

0x2E CTRL_REG5 Register (Read/Write)

0x2E: CTRL_REG5 Interrupt Configuration Register

Table 62. Interrupt Configuration Register Description

The system's interrupt controller shown in [Figure 11](#page-14-3) uses the corresponding bit field in the CTRL_REG5 register to determine the routing table for the INT1 and INT2 interrupt pins. If the bit value is logic '0' the functional block's interrupt is routed to INT2, and if the bit value is logic '1' then the interrupt is routed to INT1. One or more functions can assert an interrupt pin; therefore a host application responding to an interrupt should read the INT_SOURCE (0x0C) register to determine the appropriate sources of the interrupt.

6.8 User Offset Correction Registers

For more information on how to calibrate the 0g Offset refer to AN4069 Offset Calibration Using the MMA8452Q. The 2's complement offset correction registers values are used to realign the Zero-g position of the X, Y, and Z-axis after device board mount. The resolution of the offset registers is 2 mg per LSB. The 2's complement 8-bit value would result in an offset compensation range ±256 mg.

0x2F: OFF_X Offset Correction X Register

0x2F OFF_X Register (Read/Write)

Table 63. OFF_X Description

0x30: OFF_Y Offset Correction Y Register

0x30 OFF_Y Register (Read/Write)

Table 64. OFF_Y Description

0x31: OFF_Z Offset Correction Z Register

0x31 OFF_Z Register (Read/Write)

Table 65. OFF_Z Description

Table 66. MMA8452Q Register Map

Table 67. Accelerometer Output Data

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DETAIL G

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PACKAGE DIMENSIONS

NOTES:

- 1. ALL DIMENSIONS ARE IN MILLIMETERS.
- 2. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M-1994.
- 3. THIS IS NON JEDEC REGISTERED PACKAGE.

 $\sqrt{4}$ coplanarity applies to all leads.

5. MIN. METAL GAP SHOULD BE 0.2MM.

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